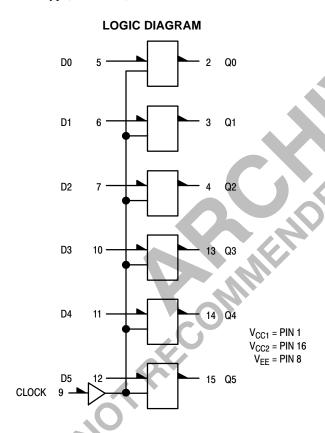
# Hex D Master/Slave Flip-Flop

The MC10176 contains six high-speed, master slave type "D" flip-flops. Clocking is common to all six flip-flops. Data is entered into the master when the clock is low. Master to slave data transfer takes place on the positive-going Clock transition. Thus, outputs may change only on a positive-going Clock transition. A change in the information present at the data (D) input will not affect the output information any other time due to the master-slave construction of this device.

- $P_D = 460 \text{ mW typ/pkg (No Load)}$
- $f_{toggle} = 150 \text{ MHz (typ)}$
- $t_r$ ,  $t_f = 2.0$  ns typ (20%–80%)



### **CLOCKED TRUTH TABLE**

С	D	Q <sub>n+1</sub>
L	Х	Q <sub>n</sub>
H*	L	L
H*	Н	Н

\*A clock H is a clock transition from a low to a high state.



### ON Semiconductor

http://onsemi.com





PDIP-16 P SUFFIX CASE 648

PLCC-20 FN SUFFIX CASE 775

**MARKING** 

MC10176P

**AWLYYWW** 

A = Assembly Location
WL = Wafer Lot

YY = Year

WW = Work Week

### **DIP PIN ASSIGNMENT**

	-		<u> </u>	
$V_{CC1}$	1	16		$V_{CC2}$
Q0	2	15		Q5
Q1	3	14		Q4
Q2	4	13		Q3
D0	5	12		D5
D1	6	11		D4
D2	7	10		D3
$V_{EE}$	8	9		CLOCK

Pin assignment is for Dual–in–Line Package.
For PLCC pin assignment, see the Pin Conversion Tables on page 18 of the ON Semiconductor MECL Data Book (DL122/D).

#### **ORDERING INFORMATION**

Device	Package	Shipping
MC10176L	CDIP-16	25 Units / Rail
MC10176P	PDIP-16	25 Units / Rail
MC10176FN	PLCC-20	46 Units / Rail

#### **ELECTRICAL CHARACTERISTICS**

		Pin	Test Limits  -30°C +25°C ++			1 0	5°C			
Charactariatia	Cumbal	Under	Min	Max	Min	1	Max	H8:	Max	l I Im
Characteristic Power Supply Drain Current	Symbol	Test 8	IVIIII	121	IVIIII	<b>Typ</b> 88	110	IVIIII	121	<b>Un</b> i mAd
Input Current	l <sub>E</sub>	5		350		00	220		220	μAd
input Guirent	I <sub>inH</sub>	9		495			310		310	
	I <sub>inL</sub>	5 9	0.5 0.5		0.5 0.5			0.3 0.3		μAd
Output Voltage Logic 1	V <sub>OH</sub>	2† 15†	-1.060 -1.060	-0.890 -0.890	-0.960 -0.960		-0.810 -0.810	-0.890 -0.890	-0.700 -0.700	Vd
Output Voltage Logic 0	V <sub>OL</sub>	2† 15†	-1.890 -1.890	-1.675 -1.675	-1.850 -1.850		-1.650 -1.650	-1.825 -1.825	-1.615 -1.615	Vd
Threshold Voltage Logic 1	V <sub>OHA</sub>	2† 15†	-1.080 -1.080		-0.980 -0.980			-0.910 -0.910		Vd
Threshold Voltage Logic 0	V <sub>OLA</sub>	2† 15†		-1.655 -1.655			-1.630 -1.630		-1.595 -1.595	Vd
Switching Times (50Ω Load) Clock Input										ns
Propagation Delay	t <sub>9+2+</sub> t <sub>9+2-</sub>	2 2	1.6 1.6	4.6 4.6	1.6 1.6		4.5 4.5	1.6 1.6	5.0 5.0	
		2	1.0	4.1	1.1		4.0	1.1	4.4	
Rise Time (20 to 80%)	t <sub>2+</sub>		4.0	4.1	1.1	0	4.0	1.1	4.4	
Rise Time (20 to 80%) Fall Time (20 to 80%)	t <sub>2+</sub> t <sub>2-</sub>	2	1.0	70.1						1
		2	2.5	A.	2.5			2.5		ns
Fall Time (20 to 80%)	t <sub>2-</sub>				2.5	0,		2.5 1.5		
Fall Time (20 to 80%) Setup Time	$t_{2-}$ $t_{\rm setup}$ $t_{\rm hold}$ $f_{\rm tog}$	2 2 2	2.5 1.5 125		1.5 125	150	V <sub>IHr</sub>	1.5 125		ns ns MH

†Output level to be measured after a clock pulse	has bee	n applied to	the C In	out (Pin 9)		Thmax
					_ '	└── ∨ <sub>ILmin</sub>

#### **ELECTRICAL CHARACTERISTICS** (continued)

			TEST VOLTAGE VALUES (Volts)					
	@ Test Te	mperature	V <sub>IHmax</sub>	V <sub>ILmin</sub>	V <sub>IHAmin</sub>	V <sub>ILAmax</sub>	V <sub>EE</sub>	
		-30°C	-0.890	-1.890	-1.205	-1.500	-5.2	
+25°C			-0.810	-1.850	-1.105	-1.475	-5.2	
	+85°			-1.825	-1.035	-1.440	-5.2	
		Pin	TEST V	OLTAGE AP	PLIED TO P	NS LISTED	BELOW	04 \
Characteristic	Symbol	Under Test	V <sub>IHmax</sub>	V <sub>ILmin</sub>	V <sub>IHAmin</sub>	V <sub>ILAmax</sub>	V <sub>EE</sub>	(V <sub>CC</sub> ) Gnd
Power Supply Drain Current	Ι <sub>Ε</sub>	8					8	1, 16
Input Current	l <sub>inH</sub>	5 9	5 9				8 8	1, 16 1, 16
	I <sub>inL</sub>	5 9		5 9			8 8	1, 16 1, 16
Output Voltage Logic 1	V <sub>OH</sub>	2† 15†	5 12				8 8	1, 16 1, 16
Output Voltage Logic 0	V <sub>OL</sub>	2† 15†		5 12			8 8	1, 16 1, 16
Threshold Voltage Logic 1	V <sub>OHA</sub>	2† 15†			5 12		8 8	1, 16 1, 16
Threshold Voltage Logic 0	V <sub>OLA</sub>	2† 15†				5 12	8 8	1, 16 1, 16
Switching Times (50Ω Load)			+1.11Vdc	+0.31V	Pulse In	Pulse Out	-3.2 V	+2.0 V
Clock Input Propagation Delay	t <sub>9+2+</sub> t <sub>9+2-</sub>	2 2			5, 9 5, 9	2 2	8 8	1, 16 1, 16
Rise Time (20 to 80%)	t <sub>2+</sub>	2			5, 9	2	8	1, 16
Fall Time (20 to 80%)	t <sub>2-</sub>	2			5, 9	2	8	1, 16
Setup Time	t <sub>setup</sub>	2			5, 9	2	8	1, 16
Hold Time	t <sub>hold</sub>	2			5, 9	2	8	1, 16
Toggle Frequency (Max)	f <sub>tog</sub>	2					8	1, 16

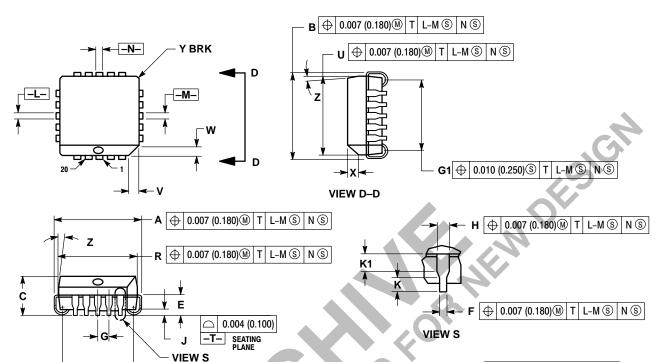
<sup>†</sup> Output level to be measured after a clock pulse has been applied to the C Input (Pin 9) VILmin VILmin

Each MECL 10,000 series circuit has been designed to meet the dc specifications shown in the test table, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow greater than 500 linear fpm is maintained. Outputs are terminated through a 50–ohm resistor to –2.0 volts. Test procedures are shown for only one gate. The other gates are tested in the same manner.

#### PACKAGE DIMENSIONS

#### PLCC-20 **FN SUFFIX**

PLASTIC PLCC PACKAGE CASE 775-02 ISSUE C



#### NOTES:

- OTES:

  1. DATUMS -L-, -M-, AND -N- DETERMINED WHERE TOP OF LEAD SHOULDER EXITS PLASTIC BODY AT MOLD PARTING LINE.

  2. DIMENSION G1, TRUE POSITION TO BE MEASURED AT DATUM -T-, SEATING PLANE.

  3. DIMENSIONS R AND U DO NOT INCLUDE MOLD FLASH. ALLOWABLE MOLD FLASH IS 0.010 (0.250) PER SIDE.

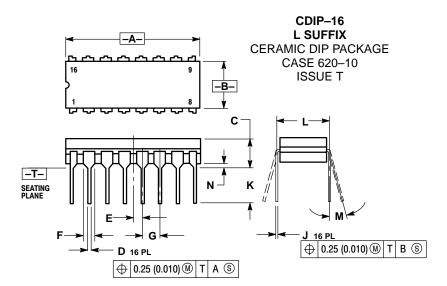
  4. DIMENSIONING AND TOLERANCING PER ANSI V14 5M 1982
- Y14.5M, 1982. CONTROLLING DIMENSION: INCH.
- THE PACKAGE TOP MAY BE SMALLER THAN THE PACKAGE BOTTOM BY UP TO 0.012 (0.300). DIMENSIONS R AND U ARE DETERMINED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY EXCLUSIVE OF MOLD FLASH, TIE BAR BURRS, GATE BURRS AND INTERLEAD FLASH, BUT INCLUDING ANY MISMATCH BETWEEN THE TOP AND BOTTOM OF THE PLASTIC BODY.
- DIMENSION H DOES NOT INCLUDE DAMBAR PROTRUSION OR INTRUSION. THE DAMBAR PROTRUSION(S) SHALL NOT CAUSE THE H DIMENSION TO BE GREATER THAN 0.037 (0.940). THE DAMBAR INTRUSION(S) SHALL NOT CAUSE THE H DIMENSION TO BE SMALLER THAN 0.025 (0.635).

	INC	HES	MILLIM	ETERS
DIM	MIN	MAX	MIN	MAX
Α	0.385	0.395	9.78	10.03
В	0.385	0.395	9.78	10.03
С	0.165	0.180	4.20	4.57
Е	0.090	0.110	2.29	2.79
F	0.013	0.019	0.33	0.48
G	0.050	BSC	1.27	BSC
Н	0.026	0.032	0.66	0.81
J	0.020		0.51	
K	0.025		0.64	
R	0.350	0.356	8.89	9.04
U	0.350	0.356	8.89	9.04
٧	0.042	0.048	1.07	1.21
W	0.042	0.048	1.07	1.21
Χ	0.042	0.056	1.07	1.42
Υ		0.020		0.50
Z	2°	10°	2°	10 °
G1	0.310	0.330	7.88	8.38
K1	0.040		1.02	

G1 ⊕ 0.010 (0.250)③ T L-M ⑤ N ⑤

OENICE NOT RECO

#### PACKAGE DIMENSIONS



#### NOTES:

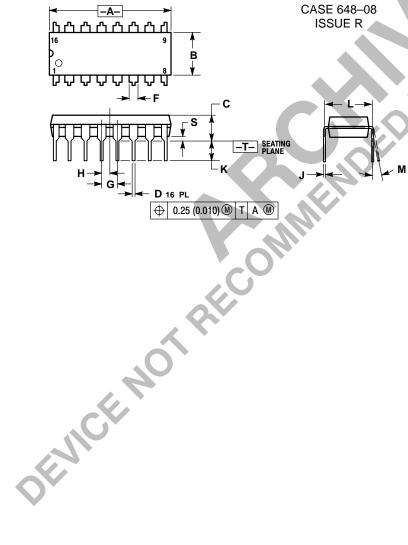
- DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
   CONTROLLING DIMENSION: INCH.
   DIMENSION LTO CENTER OF LEAD WHEN CONTROLLING DIMENSION LTO CENTER OF LEAD WHEN

- FORMED PARALLEL

  DIMENSION F MAY NARROW TO 0.76 (0.030)
  WHERE THE LEAD ENTERS THE CERAMIC
  BODY.

	INC	HES	MILLIN	IETERS	
DIM	MIN	MAX	MIN	MAX	
Α	0.750	0.785	19.05	19.93	
В	0.240	0.295	6.10	7.49	
C		0.200		5.08	
D	0.015	0.020	0.39	0.50	
E	0.050	BSC	1.27 BSC		
F	0.055	0.065	1.40	1.65	
G	0.100	BSC	2.54	BSC	
Н	0.008	0.015	0.21	0.38	
K	0.125	0.170	3.18	4.31	
L	0.300	BSC	7.62	BSC	
M	0 °	15°	0 0	15°	
N	0.020	0.040	0.51	1.01	

#### PDIP-16 **P SUFFIX** PLASTIC DIP PACKAGE CASE 648-08 ISSUE R



- NOTES:
  1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
  2. CONTROLLING DIMENSION: INCH.
  3. DIMENSION L TO CENTER OF LEADS WHEN FORMED PARALLEL.
  4. DIMENSION B DOES NOT INCLUDE MOLD FLASH.
  5. ROUNDED CORNERS OPTIONAL

	INC	HES	MILLIN	IETERS	
DIM	MIN	MAX	MIN	MAX	
Α	0.740	0.770	18.80	19.55	
В	0.250	0.270	6.35	6.85	
С	0.145	0.175	3.69	4.44	
D	0.015	0.021	0.39	0.53	
F	0.040	0.70	1.02	1.77	
G	0.100	BSC	2.54 BSC		
Н	0.050	BSC	1.27	BSC	
J	0.008	0.015	0.21	0.38	
K	0.110	0.130	2.80	3.30	
L	0.295	0.305	7.50	7.74	
M	0°	10°	0°	10 °	
S	0.020	0.040	0.51	1.01	

## **Notes**



## **Notes**





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